MOSFET - Power, Single **N-Channel, Power33**

25 V, 1.3 mΩ, 150 A

NTTFS1D8N02P1E

Features

- Small Footprint for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- DC-DC Converters
- Power Load Switch
- Notebook Battery Management

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	25	V
Gate-to-Source Voltage			V _{GS}	+16, -12	V
Continuous Drain Current R _{BJC}		T _C = 25°C	I _D	150	Α
(Note 1)	Steady	T _C = 85°C	1	108	
Power Dissipation R _{θJC} (Note 1)	State	T _C = 25°C	P _D	46	W
Continuous Drain		T _A = 25°C	I _D	36	Α
Current R _{θJA} (Notes 1, 3)	Steady	T _A = 85°C		26	
Power Dissipation R _{θJA} (Notes 1, 3)	State	T _A = 25°C	P _D	2.7	W
Continuous Drain		T _A = 25°C	I _D	20	Α
Current R _{θJA} (Notes 2, 3)	Steady	T _A = 85°C		14	
Power Dissipation R _{θJA} (Notes 2, 3)	State	T _A = 25°C	P _D	0.8	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	508	Α
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 48.3 A, L = 0.1 mH) (Note 4)			E _{AS}	117	mJ
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C
Lead Temperature Soldering Reflow for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Surface-mounted on FR4 board using a 1 in² pad size, 2 oz Cu pad.
- 2. Surface-mounted on FR4 board using minimum pad size, 2 oz Cu pad.
- The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted. Actual continuous current will be limited by thermal & electro- mechanical application board design. $R_{\theta CA}$ is determined by the user's board design. 4. 100% UIS tested at L = 0.1 mH, $I_{AV}=32$ A.

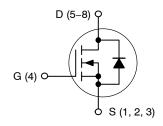


ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
25 V	1.3 mΩ @ 10 V	150 4
20 V	1.8 mΩ @ 4.5 V	150 A

NMOS





PQFN8 (Power33) CASE 483AW

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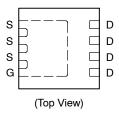
MARKING DIAGRAM

2EMN **AYWWZZ**

2EMN = Specific Device Code Α = Assembly Location = Year WW = Work Week

PIN CONNECTIONS

= Assembly Lot Code



ORDERING INFORMATION

See detailed ordering and shipping information on page 5 of this data sheet.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Case - Steady State (Note 1)	$R_{ heta JC}$	2.7	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	47	
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	152	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 1 mA		25			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /	I _D = 1 mA, ref to 25°C			16		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			10	
		$V_{DS} = 20 \text{ V}$	T _J = 125°C			100	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = +16 V, -12 V				±100	±nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 660 \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V _{GS(TH)} /T _J	I _D = 660 μA, ref to 25°C			-4.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 17 A		1.05	1.3	mΩ
		V _{GS} = 4.5 V	I _D = 13 A		1.3	1.8	
Forward Transconductance	9FS	V _{DS} = 5 V, I _D = 17 A			118		S
Gate Resistance	R_{G}	T _A = 25°C			0.6		Ω
CHARGES & CAPACITANCES							
Input Capacitance	C _{ISS}	V _{GS} = 0 V, V _{DS} = 13 V, f = 1 MHz			2980		
Output Capacitance	C _{OSS}				805		pF
Reverse Capacitance	C _{RSS}				41		
Total Gate Charge	$Q_{G(TOT)}$	V _{GS} = 4.5 V, V _{DS} = 13 V; I _D = 17 A			17.1		nC
Threshold Gate Charge	Q _{G(TH)}				4		
Gate-to-Drain Charge	Q_{GD}				2.7		
Gate-to-Source Charge	Q_{GS}				7]
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 13 V; I _D = 17 A			39		
SWITCHING CHARACTERISTICS, V _{GS} = 4.5	V (Note 5)						
Turn-On Delay Time	t _{d(ON)}				21.3		
Rise Time	t _r	V _{GS} = 4.5 V, V _{DI}	₀ = 13 V,		8]
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 17 \text{ A}, R_G = 6 \Omega$			30		ns
Fall Time	t _f				7		
SWITCHING CHARACTERISTICS, V _{GS} = 10	V (Note 5)						
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DD} = 13 V, I_{D} = 17 A, R_{G} = 6 Ω			13		
Rise Time	t _r				2.8		ns ns
Turn-Off Delay Time	t _{d(OFF)}				44		
Fall Time	t _f				5.4		
SOURCE-TO-DRAIN DIODE CHARACTERI	STICS						
Forward Diode Voltage	V_{SD}	V_{SD} $V_{GS} = 0 \text{ V},$ $T_{J} = 28$			0.77	1.2	
	I _S = 17 A		T _J = 125°C		0.61		
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dI/dt = 100 A/ μ s, I_{S} = 17 A			34		ns
	Q_{RR}				22		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

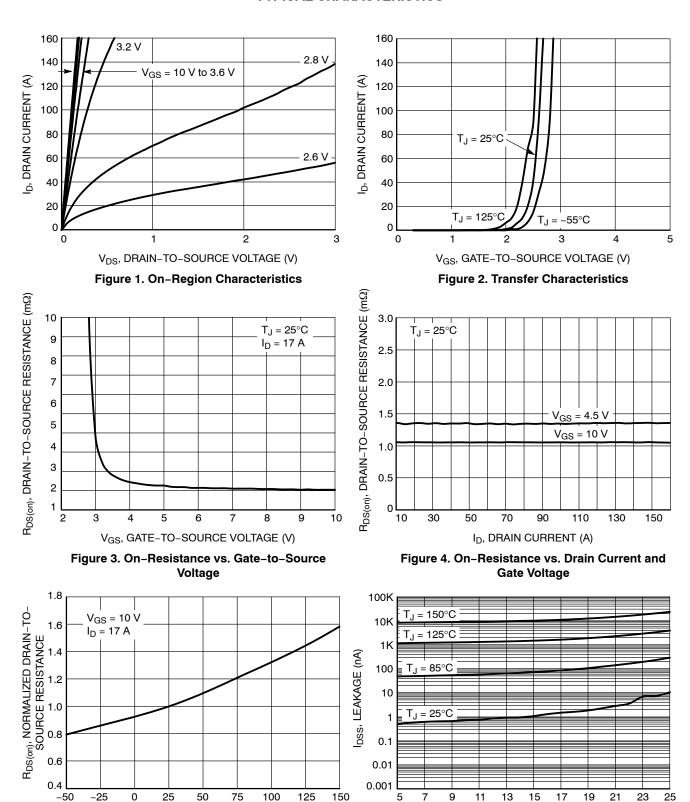


Figure 5. On–Resistance Variation with Temperature

T_J, JUNCTION TEMPERATURE (°C)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

TYPICAL CHARACTERISTICS

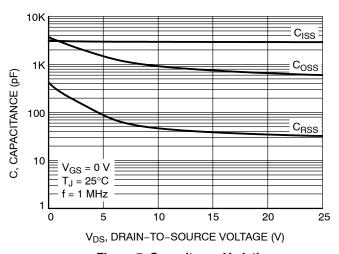


Figure 7. Capacitance Variation

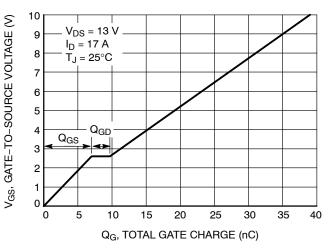


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

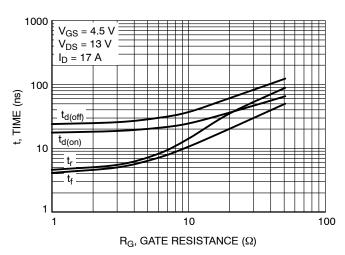


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

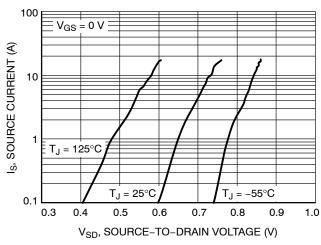


Figure 10. Diode Forward Voltage vs. Current

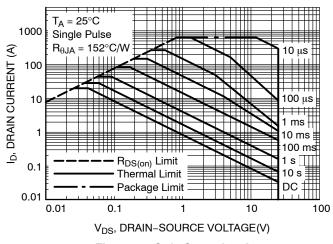


Figure 11. Safe Operating Area

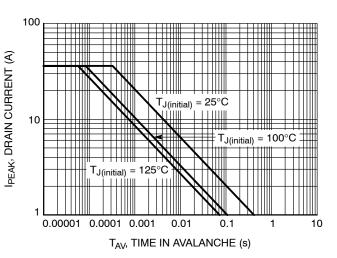


Figure 12. $I_{\mbox{\scriptsize PEAK}}$ vs. Time in Avalanche

TYPICAL CHARACTERISTICS

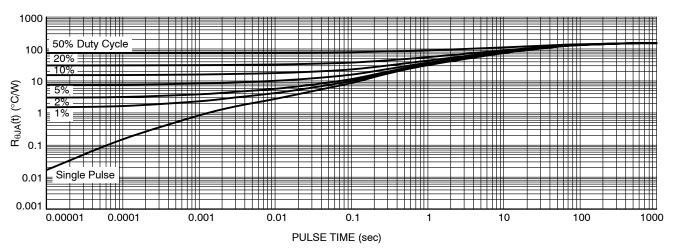


Figure 13. Thermal Characteristics

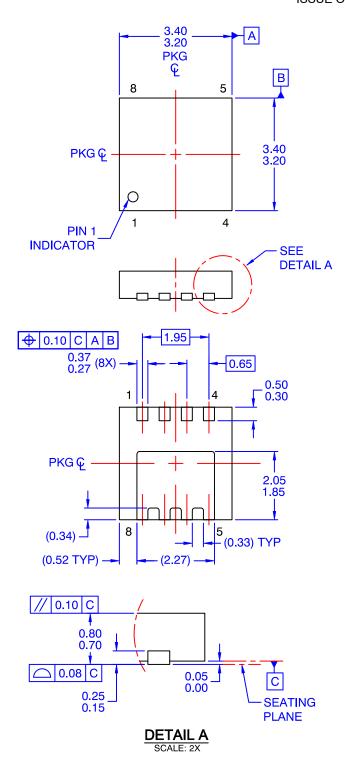
ORDERING INFORMATION

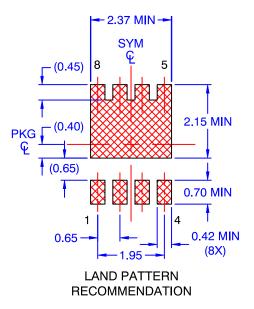
Device	Marking	Package	Shipping [†]
NTTFS1D8N02P1E	2EMN	Power33 (Pb-Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

PQFN8 3.3X3.3, 0.65P CASE 483AW ISSUE O





NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

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